EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S5	67018	electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:17
S6	79540	pattern same wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:18
S7	113525	(initial first) with design	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:19
S8	29556	layout same generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:19
S9	30	S5 and S6 and S7 and S8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:20
S10	22	S5 and S6 and S7 and S8 and simulat$3 and modif$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:28
S11	21	S5 and S6 and S7 and S8 and simulat$3 and modif$5 and structure	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:28
S12	20	S5 and S6 and S7 and S8 and simulat$3 and modif$5 and structure and process with variation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:29

S13	20	S5 and S6 and S7 and S8 and simulat$3 and modif$5 and structure and process with variation and portion	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:29
S14	20	S5 and S6 and S7 and S8 and simulat$3 and modif$5 and structure and process with variation and portion and size	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:30
S15	17	S5 and S6 and S7 and S8 and simulat$3 and modif$5 and structure and process with variation and portion and size and adjacent	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:33
S16	0	S5 and S6 and S7 and S8 and simulat$3 and modif$5 and structure and process with variation and portion and size and adjacent and intensity	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/13 19:33
S17	16	layout adj generat$3 and modif$7 with design and electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 13:28
S18	6	layout adj generat$3 and modif$7 with design same electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 13:28
S19	1	(actual desired) with characteristic same match$3 same modif$7 same (netlist initial adj3 design)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:29
S20	0	(actual desired) with characteristic same match$3 same modif$7 same (netlist initial adj3 design) and layout with generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:28

S21	0	(actual desired) with characteristic same match$3 same modif$7 same (netlist initial adj3 design) and layout same generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:29
S22	0	(actual desired) with characteristic same match$3 same modif$7 same (netlist initial adj3 design) and (physical layout) same generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:29
S23	14540	layout with generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:30
S24	67018	electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:30
S25	3088	simulat$3 same structure same pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:31
S26	169262	(actual desired) same (design characteristic)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:32
S27	17024	(actual desired) same (design characteristic) same modif$7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:33
S28	9	S23 and S24 and S25 and S27	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:44

S29	190	slope near4 edge with intensity	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:47
S30	0	S28 and S29	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:47
S31	22	process adj2 variation same slope and layout	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:50
S32	0	S31 and S28	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:48
S33	20	process adj2 variation same slope and layout and feature	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:58
S34	3	S23 and S33	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:53
S35	1	S23 and S33 and S24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:53
S36	9	S33 and S24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 14:55

S37	344	slope with (edge intensity) same (larger smaller) same variation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 15:00
S38	0	S37 and S23 and S24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/14 15:02
S43	67024	electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:01
S44	8021	electrical adj characteristic and model$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:01
S45	60	electrical adj characteristic same layout same simulat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:02
S46	37	electrical adj characteristic same layout same simulat$3 and pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:02
S47	27	electrical adj characteristic same layout same simulat$3 and pattern and variation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:03
S48	26	electrical adj characteristic same layout same simulat$3 and pattern and variation and structure	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:03

S49	20	electrical adj characteristic same layout same simulat$3 and pattern and variation and structure and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:03
S50	17	electrical adj characteristic same layout same simulat$3 and pattern and variation and structure and wafer and modif$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:03
S51	17	electrical adj characteristic same layout same simulat$3 and pattern and variation and structure and wafer and modif$5 and generat$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:04
S52	13	electrical adj characteristic same layout same simulat$3 and pattern and variation and structure and wafer and modif$5 and generat$5 with layout	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:10
S53	56	electrical adj characteristic and layout same simulat$3 and pattern and variation and structure and wafer and modif$5 and generat$5 with layout	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:14
S54	63	electrical adj characteristic and layout and simulat$3 and pattern and variation and structure and wafer and modif$5 and generat$5 with layout	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:27
S55	1342	intensity same edge same slope	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:29
S56	0	S54 and S55	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:28

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S57	1797	intensity same edge same (derivative slope)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:29
S58	0	S54 and S57	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:29
S59	1895	intensity same edge same (derivative slope logarith$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:30
S60	0	S54 and S59	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:39
S61	1226	716/2.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:39
S62	47	716/2.ccls. and variation and S43	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:52
S63	8	716/2.ccls. and variation and S43 and pattern and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:40
S64	7	layout adj simulation adj tool	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:53

S65	5	layout adj simulation adj tool and electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:54
S66	2	layout adj simulation adj tool and electrical adj characteristic and variation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:55
S67	486	layout and simulat$3 and electrical adj characteristic and variation and pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:55
S68	212	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:55
S69	58	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:56
S70	58	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:56
S71	58	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:56
S72	57	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat$3 and modif$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:58

S73	0	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat$3 and modif$5 and netlist	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:57
S74	0	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat$3 and modif$5 and (HDL netlist)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:57
S75	4	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat$3 and modif$5 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 10:58
S76	13	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and (derivative slope) and structure and generat$3 and modif$5 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 11:03
S77	7	layout and simulat$3 and electrical adj characteristic and variation and pattern and intensity and (derivative slope) same position and structure and generat$3 and modif$5 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 11:03
S78	960	(slope derivative) same (larger small greater less more) same edge same intensity	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 13:39
S79	27	(slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 13:42
S80	20	(slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 13:42

S81	20	(slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation and process	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 13:45
S82	2	(slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation and process and electrical adj characteristic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/16 13:43